

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/624,670	LI ET AL.	
Examiner	Shin-Lin Chen	Art Unit 1632	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
424	93.2		
435	320.1		
435	455		
536/23.1, 24.1, AU interference search		10/17/2007	<i>GJL</i>